

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L9	2	("20050146714").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2008/04/22 10:50
L10	1	((cd (critical adj dimension) (line adj width) (spac\$3 adj width)) with microscope) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 10:52
L11	2	(operator (field adj2 view)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 11:56
L12	0	(operator same (field adj2 view)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 11:59
L13	1	(electron adj beam) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 12:02
L14	0	(cluster\$3 with (field adj2 view)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 12:47
L15	0	(cluster\$3 same (field adj2 view)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 12:48
L16	0	((cluster\$3 group\$4) same (field adj2 view)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 12:48
L17	1	((cluster\$3 group\$4) and (field adj2 view)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 12:48
L18	1	(corner same (opc proximity)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 12:57
L19	1	(beam same (cd-sem sem microscope)) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 13:05
L20	0	(defect same compar) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 13:10
L21	2	(defect same compar\$3) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 13:10
L22	0	(auto adj focus3) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 13:33

L23	1	(auto adj focus\$3) and 9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/22 13:34
L24	2	("6868175").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2008/04/22 13:47
S1	4	((("20020093350") or ("6559662")).PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2008/04/20 17:56
S2	1427866	beam	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 17:56
S3	4	S1 and S2	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 17:57
S4	0	focus and S3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 17:57
S5	0	cd and S3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 17:57
S6	2	layer and S3	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 17:58
S7	38	NEHMADI-YOUVAL.in. ABRAHAM-ZAMIR.in. SOD- MORIAH-IL.in. ERAN- YAIR.in. OFEK-CHEN.in. COHEN-YARON.in. BEN- PORATH-ARIEL.in.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 18:20
S8	21	beam and S7	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 18:20
S9	16	layer and S8	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 18:21
S10	4	(shift\$3 near4 image) and S9	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/20 18:21
S11	75642	\$3sem	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:01
S12	40236	scan\$4 adj electron adj microscope	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:02
S13	21360	S11 and S12	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:02
S14	17729	beam and S12	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:03

S15	9146	feature and S14	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:03
S16	3091	((critical adj dimension) cd (line adj width)) and S15	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:04
S17	815	simulat\$3 and S16	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:05
S18	141	(eda cad) and S17	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:06
S19	63	opc and S18	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 08:06
S20	0	S12 and (field adj of adj view)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:18
S21	0	S11 and (field adj of adj view)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:19
S22	790	CD-SEM	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:20
S23	0	S22 and (field adj of adj view)	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:20
S24	1255	CD-SEM ((critical adj dimension) near4 sem) ((critical adj dimension) near4 (scan\$4 adj electron adj microscope))	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:41
S25	22	(auto adj focus\$3) and S24	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:42
S26	4	opc and S25	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 11:58
S27	16737	(applied adj materials). as.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:09
S28	786	(electron adj beam) and S27	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:10
S29	80894	field adj2 view	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:11
S30	71	S28 and S29	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:11

S31	8	correlation and S30	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:11
S32	20	simulat\$3 and S30	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:21
S33	0	correlation and S32	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:21
S34	20	S29 and S32	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:21
S35	4	repetitive and S34	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:22
S36	0	opc and S34	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:23
S37	12	((critical adj dimension) od (line adj width)) and S34	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	ON	2008/04/21 14:24
S38	2	("6868175").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT	OR	OFF	2008/04/21 16:07

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